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IN THE CLAIMS:

Please amend the claims to read as follows:

1-6. (Canceled)

7. (Currently amended) A semiconductor device comprising:

first and second power source lines;

a plurality of output circuits including at least first and second output circuits, each of said output circuits including a combination of first and second transistors connected together in series via a first node and between said first power source line and said second power source line;

a plurality of output terminals each disposed for one of said output circuits, said first node being connected to a corresponding one of said output terminals; and

a control circuit for controlling said output circuits during a test mode to turn ON said first and second transistors of said first output circuit, ~~and to turn ON and OFF~~ one of said first transistor and said second transistor, ~~respectively,~~ of said second output circuit, and to turn OFF another of said first transistor and said second transistor of said second output circuit.

8. (Currently amended) The semiconductor device according to claim 7, wherein said control circuit turns OFF said first and second transistors of all said output circuits other than said first and second output circuits.

9. (Currently amended) The semiconductor device according to claim 7, wherein said first and second transistors ~~are~~ comprise p-ch and n-ch MIS transistors, respectively.

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10. (Currently amended) The semiconductor device according to claim 7, wherein at least one of said first and second transistors ~~includes~~ comprises a plurality of transistor elements connected in parallel.

11. (Currently amended) The semiconductor device according to claim 7, wherein said control circuit ~~includes~~ comprises a decoder for decoding external signals to deliver a control signal for controlling said output circuits.

12. (Original) The semiconductor device according to claim 11, wherein said control signal selects a potential to be provided to control electrodes of said first and second transistors.

13. (Currently amended) The semiconductor device according to claim 7, further ~~comprising~~ comprising:

a functional circuit block connected between said first power source line and said second power source ~~line~~, line; and

a control switch for isolating said functional circuit block from said first or second power source line during said test mode.

14. (Original) The semiconductor device according to claim 7, wherein said first and second output circuits are connected between said first power source line and said second power source line via a common branch line extending from said first or second power source line.